

**LIST OF REFERENCES CITED BY APPLICANT**

(Use Several Sheets if Necessary)

DOCKET NO.: 2640/1G820-US1
 APPLICANT : Eitan T. WIENER, et al.

SERIAL NO: not yet assigned
 FILING DATE: Concurrently herewith
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U.S. PATENT DOCUMENTS

*EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE
BCP	1. 2,917,691	12/15/59	DePrisco et al.	318	118	07/10/56
	2. 5,001,649	03/19/91	Lo et al.	364	484	09/16/88
	3. 5,112,300	05/12/92	Ureche	604	22	04/03/90
	4. 5,026,387	06/25/91	Thomas	606	169	03/12/90
	5. 5,180,363	01/19/93	Idemoto et al.	202	32	12/23/91
	6. 5,400,267	03/21/95	Denen et al.	364	552	12/08/92
	7. 5,425,704	06/20/95	Sakurai et al.	604	22	06/09/92
	8. 5,449,370	09/12/95	Vaitekunas	606	169	05/12/93
	9. 5,630,420	05/20/97	Vaitekunas	128	662.03	09/29/95
	10. 5,707,369	01/13/98	Vaitekunas et al.	606	31	04/24/95
	11. 5,879,364	03/09/99	Bromfield et al.	606	169	09/30/97
	12. 5,968,007	10/19/99	Simon et al.	604	22	05/01/97
	13. 6,017,354	01/25/00	Culp et al.	606	170	08/15/96
	14. 6,019,775	02/01/00	Sakurai	606	169	06/23/98
	15. 6,066,135	05/23/00	Honda	606	39	09/22/98
	16. 6,090,123	07/18/00	Culp et al.	606	180	02/12/99

FOREIGN PATENT DOCUMENTS

*EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	17. 2000-175926	06/27/00	Japan			Abstract

EXAMINER: Bradford C. Furtuk

DATE CONSIDERED: 3/10/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.